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Application/Control No.	Applicant(s)/Patent under Reexamination
08/427,866	SUGIYAMA ET AL.
Examiner	Art Unit
Hai C. Pham	2861

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	SEAR	CHED	
Class	Subclass	Date	Examiner
369	94, 44.23, 100, 275.1- 275.4	11/6/2006	HP
	286, 288		

INT	ERFERENC	E SEARCH	ED
Class	Subclass	Date	Examiner
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EAST Text Search	11/6/2006	EXMR _.
EAST Text Search	11/6/2006	ΗР
EAST Text Search	11/6/2006	НР
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